

ABSTRACT

A test connector (10) includes a connector body (30) with terminals therein, a lid (20), four guiding mechanisms (50), and two pressing mechanisms (40). The connector body comprises an outer housing (34) and an inner housing (32) for receiving an IC package (80). Each pressing mechanism comprises a first shaft (44) attached to the lid, a second shaft (46) mounted to the outer housing, two operating levers (42) engaged between the first and second shafts, and a leaf spring (48) mounted to the first shaft. When the lid is in an upper position, the pressing mechanisms are in a first position in which the leaf springs are disengaged from the IC package, while when the lid is in a lower position, the pressing mechanisms are moved to a second position in which the leaf springs are engaged with the IC package thereby the IC package can be tested.